## Search Notes



Application/Control	No.

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Reexamination

CHOI ET AL.

Applicant(s)/Patent Under

Examiner

Nguyen, Jennifer T

Art Unit

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## **SEARCHED**

Class	Subclass	Date	Examiner
345	60-72,88-104,33,41,42	1/19/08	JN

S	Date	Examiner
SEARCH NOTES		

Search NotesDateExaminereast, iEEE, JPO,EPO, USPAT, US-PGPUB, DERWENT,Inventor, Claim<br/>interference1/19/08JN

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner
315	169.1,169.4	1/19/08	JN
313	582-586	1/19/08	jn

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